Fundamentals of Nanotransistors

Unit 3: The Ballistic Nanotransistor

Lecture 3.5: The Velocity at the VS

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Current is velocity times charge

 $I_{DS} = W \left| Q_n \left(V_{GS}, V_{DS} \right) \right| \left\langle \upsilon \left(V_{GS}, V_{DS} \right) \right\rangle$

Average velocity at the top of the barrier



$$I_{DS} = W |Q_n(0)| \upsilon_T \frac{\left(1 - e^{-qV_{DS}/k_BT}\right)}{\left(1 + e^{-qV_{DS}/k_BT}\right)}$$

$$I_{DS} = W |Q_n(0)| \langle \upsilon_x(x=0) \rangle$$

$$\langle \upsilon_x(x=0)\rangle = \upsilon_T \frac{\left(1-e^{-qV_{DS}/k_BT}\right)}{\left(1+e^{-qV_{DS}/k_BT}\right)}$$

velocity at the top of the barrier?

(nondegenerate carrier statistics)

Velocity vs. V_{DS}



$$\langle \upsilon_x(x=0)\rangle = \upsilon_T \frac{(1-e^{-qv_{DS}/k_BT})}{(1+e^{-qV_{DS}/k_BT})}$$

Velocity for small V_{DS}

$$\langle \upsilon(x=0) \rangle = \upsilon_{T} \frac{\left(1 - e^{-qV_{DS}/k_{B}T}\right)}{\left(1 + e^{-qV_{DS}/k_{B}T}\right)}$$

$$V_{DS} << k_{B}T/q$$

$$\langle \upsilon(x=0) \rangle = \frac{\upsilon_{T}}{2(k_{B}T/q)} V_{DS}$$

$$\langle \upsilon(x=0) \rangle = \frac{\upsilon_{T}L}{2(k_{B}T/q)} \frac{V_{DS}}{L}$$

$$\mu_{B} = \frac{\upsilon_{T}L}{2(k_{B}T/q)} \operatorname{cm}^{2}/\mathrm{V-s}$$

$$\mathsf{``ballistic mobility''}$$

$$\langle \upsilon(x=0) \rangle = \mu_{B}\mathcal{E}_{x}$$

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The meaning of "ballistic mobility"



$$\mu_n = \frac{\nu_T \lambda_0}{2 k_B T/q} \text{ cm}^2/\text{V-s} \qquad \mu_B = \frac{\nu_T L}{2 k_B T/q} \text{ cm}^2/\text{V-s}$$

 λ_0 : average mean-free-path for backscattering

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 $\lambda_0 \rightarrow L$

Velocity vs. V_{DS}



"Signature" of velocity saturation





ETSOI MOSFET data provided by A. Majumdar, IBM Research, 2015.

Maxwellian velocity distribution

$$f_0(E) = \frac{1}{1 + e^{(E - E_F)/k_B T}} \qquad f_0(E) \approx e^{-(E - E_F)/k_B T} \qquad E = E_C + \frac{m^* v^2}{2} \qquad v^2 = v_x^2 + v_y^2$$

$$f_0(v_x, v_y) \propto e^{-m^*(v_x^2 + v_y^2)/2k_BT}$$

$$I_0^8 \int_{v_y} \int_{-10^8} \frac{1}{v_x} \int_{v_x} \frac{1}{10^8} \int_{v_y} \frac{1}{10^8} \int_{v_$$

Filling states at the top of the barrier



(Numerical simulations of an L = 10 nm double gate Si MOSFET from J.-H. Rhew and M.S. Lundstrom, *Solid-State Electron.*, **46**, 1899, 2002)

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$$I_{DS} = W |Q_n(x=0)| v_{inj}^{ball}(\eta_{FS}) \left[\frac{1 - \mathcal{F}_{1/2}(\eta_{F2}) / \mathcal{F}_{1/2}(\eta_{F1})}{1 + \mathcal{F}_0(\eta_{F2}) / \mathcal{F}_0(\eta_{F1})} \right]$$

 $I_{ON} = W |Q_n(0)| v_{inj}^{ball}(\eta_{FS})$ High drain bias

$$\left< \left< \upsilon_x(0) \right> \right> = \upsilon_{inj}^{ball}(\eta_{FS}) = \upsilon_T \frac{\mathcal{F}_{1/2}(\eta_{FS})}{\mathcal{F}_0(\eta_{FS})}$$

ballistic injection velocity (2D carriers)



Ballistic injection velocity



Maxwell-Boltzmann vs. Fermi-Dirac statistics

Maxwell-Boltzmann statistics

$$\upsilon_{inj}^{ball} = \upsilon_T = \sqrt{\frac{2k_BT}{\pi m^*}}$$

Fermi-Dirac statistics

$$\upsilon_{inj}^{ball} = \left\langle \left\langle \upsilon_{x}^{+} \right\rangle \right\rangle = \upsilon_{T} \, rac{\mathcal{F}_{1/2}(\eta_{FS})}{\mathcal{F}_{0}(\eta_{FS})}$$

$$\eta_{FS} = \frac{E_{FS} - E_C}{k_B T}$$

$$Q_n(V_{GS}, V_{DS}) = -q \frac{N_{2D}}{2} \mathcal{F}_0(\eta_{FS}) \mathrm{m}^{-2}$$

(2D carriers and parabolic energy bands)

Key points

- $I_{DSAT} \sim (V_{GS} V_T)^1$ is the "signature" of velocity saturation.
- The velocity saturates in a ballistic MOSFET, but at the top of the barrier where the electric field is zero not near the drain where the electric field is large.
- The ballistic injection velocity increases with increasing electron density (increasing Fermi level).

Next lecture

Time to revisit the VS model.